

FL979953650

Inventor: Zachary B. Katz

Title: Methods of Forming Planarized Surfaces Over Semiconductor Substrates

Assignee: Micron Technology, Inc.

INFORMATION DISCLOSURE STATEMENT


References – See Attached Form PTO-1449

The attached form PTO-1449 is submitted in compliance with 37 CFR § 1.56. Copies of the cited art are included with the exception of U.S. patents and published U.S. applications (1276 OG 55). No admission is made regarding whether all the submitted references are prior art.

Respectfully submitted,

Dated: JANUARY 26, 2004

By: _____


David G. Latwesen, Ph.D.
Reg. No. 38,533

EL979953650

Form PTO-1449		U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE		ATTY. DOCKET NO. MI22-2445		SERIAL NO. Filed Herewith	
LIST OF ART CITED BY APPLICANT (Use several sheets if necessary)				APPLICANT Micron Technology, Inc.			
				FILING DATE Filed Herewith		GROUP Unknown	
U.S. PATENT DOCUMENTS							
*Examiner Initial		Document Number	Date	Name	Class	Subclass	Filing Date If Appropriate
	AA	6,649,503	1/18/03	Kim et al.			
	AB	6,635,586	10/21/03	Goo et al.			
	AC	6,596,607	7/22/03	Ahn			
	AD	6,489,252	12/3/2002	Goo et al.			
	AE	6,479,405	11/12/2002	Lee et al.			
	AF	6,432,843	8/13/02	Kim et al.			
	AG	6,399,438	6/4/02	Saito et al.			
	AH	6,184,143	2/6/01	Ohashi et al.			
FOREIGN PATENT DOCUMENTS							
		Document Number	Date	Country	Class	Subclass	Translation
							Yes No
	AI						
	AJ						
OTHER REFERENCES (including Author, Title, Date, Pertinent Pages, Etc.)							
	AK						
	AL						
	AM						
	AN						
	AO						
EXAMINER				DATE CONSIDERED			
<small>*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.</small>							

EL979953650

Form PTO-1449		U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE		ATTY. DOCKET NO. MI22-2445		SERIAL NO. Filed Herewith	
LIST OF ART CITED BY APPLICANT (Use several sheets if necessary)				APPLICANT Micron Technology, Inc.			
				FILING DATE Filed Herewith		GROUP Unknown	
U.S. PATENT DOCUMENTS							
*Examiner Initial	Document Number	Date	Name	Class	Subclass	Filing Date If Appropriate	
	AA	6,258,649	7/10/01	Nakamura et al.			
	AB	6,187,662	2/13/01	Usami et al.			
	AC	6,215,144	4/10/01	Saito et al.			
	AD	6,235,620	5/22/01	Saito et al.			
	AE	6,261,883	7/17/01	Koubuchi et al.			
	AF	5,169,491	12/8/92	Doan			
	AG	5,618,381	4/8/97	Doan et al.			
	AH						
FOREIGN PATENT DOCUMENTS							
	Document Number	Date	Country	Class	Subclass	Translation	
						Yes	No
	AI						
	AJ						
OTHER REFERENCES (including Author, Title, Date, Pertinent Pages, Etc.)							
	AK						
	AL						
	AM						
	AN						
EXAMINER				DATE CONSIDERED			
<small>*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.</small>							